

Scanning Probe Microscope/Atomic Force Microscope

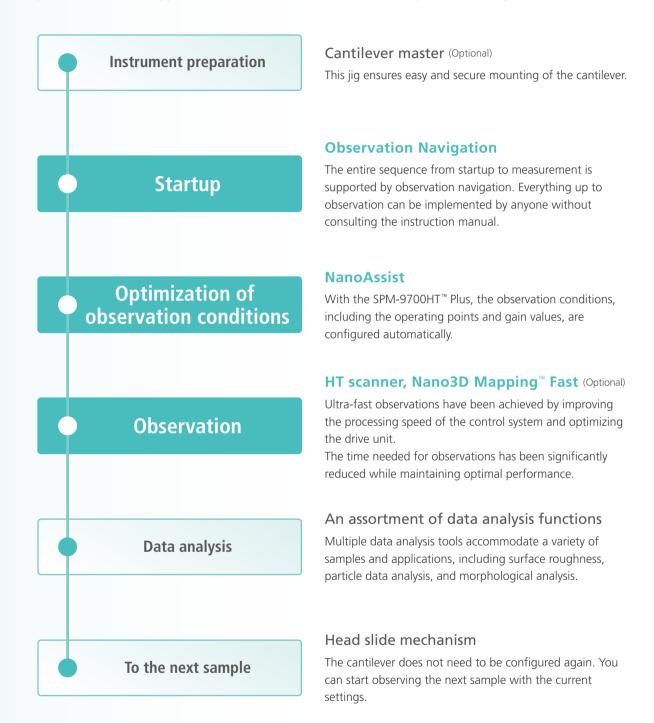
SPM-9700HT Plus



Observations Independent of the Operator



The system and software are equipped with Analytical Intelligence, our user support technology that provides maximum support for the overall workflow, from data acquisition to analysis.





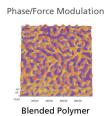
 $Analytical\ Intelligence\ is\ a\ new\ concept\ for\ analytical\ instruments\ proposed\ by\ Shimadzu.$

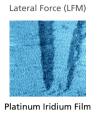
The system and software operate like an experienced engineer. The status and the quality of the results are determined automatically, and users are given feedback and solutions for problems.

This compensates for differences in knowledge and experience with regard to the analytical instrument, ensuring data reliability.

Application Mode Accommodates an Assortment of Samples





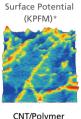












(MFM)*

Magnetic Thin Film

Magnetic Force



Positive Battery Electrode

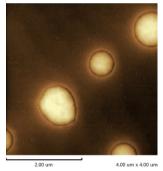
n Film Cellulose Nanofibers

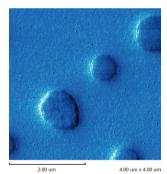
s Particle Distribution

NEW Nano3D Mapping Fast (Optional)

The time required for physical property mapping has been significantly reduced compared to the previous machine (SPM-9700HT). The shorter mapping time enables stable physical property evaluation.

Observation time
Approx.
27 min





Surface Shape

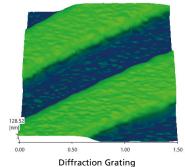
Adhesive Force

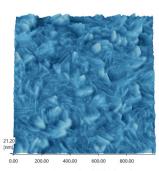
NEW NanoAssist Optimizes Observation Conditions



Only the observation range needs to be set. Other observation conditions are set automatically.

Shape Images Obtained with NanoAssist





Vapor-Deposited Nb Coating

CN1/Polymer Composite Material

^{*} Option

High-Throughput Observations

Head Slide Mechanism

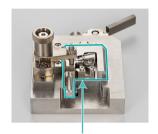
The design allows space around the sample, while maintaining a high level of rigidity.

- Samples can be replaced without removing the cantilever holder.
- Samples can be accessed even during SPM observations.
- Samples are approached automatically, regardless of the sample thickness.



Even small cantilevers can be attached with ease.





Cantilever holder

Installation Specifications

Installation Environment

The following conditions are preferable for the installation environment.

Temperature 23 °C ± 5 °C

Humidity 60 % max. (no condensation)

Power Supply

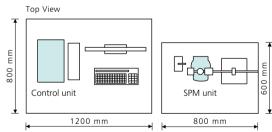
The power supply listed is required for operating this instrument. SPM-9700HT Plus

Single-phase 100 to 120 V, 50/60 Hz, 15 A, 2 circuits Grounding Type D grounding (maximum resistance 100 Ω)

- The above-mentioned is the power supply for the basic SPM-9700HT Plus specifications. This will change depending on the optional configuration. For details, refer to the specifications.
- Size and Weight

W180 × D255 × H260 mm, 5.5 kg SPM unit: Control unit: W250 x D420 x H454 mm, 18.5 kg





- This figure is one example of a configuration.
- The sizes of the OA table and desk-type air-spring vibration damper are for reference

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